

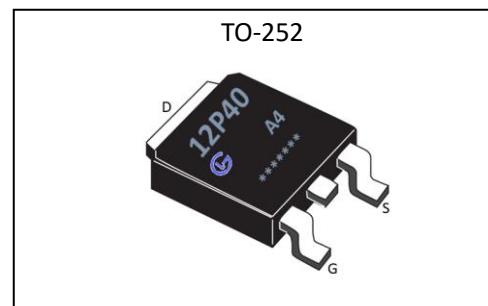
**General Description:**

The GL12P40A4 uses advanced trench technology and design to provide excellent  $R_{DS(ON)}$  with low gate charge. It can be used in a wide variety of applications. The package form is TO-252, which accords with the RoHS standard.

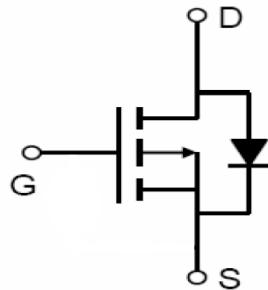
$V_{DSS}$	-40	V
$I_D$	-12	A
$P_D$	45	W
$R_{DS(ON)type}$	26	$m\Omega$

**Features:**

- $R_{DS(ON)} < 35m\Omega$  @  $V_{GS}=10V$  (Typ26mΩ)
- High density cell design for ultra low  $R_{ds(on)}$
- Fully characterized avalanche voltage and current
- Excellent package for good heat dissipation


**Applications:**

- Power switching application
- Hard switched and high frequency circuits
- Uninterruptible power supply

**Inner Equivalent Principium Chart**

**Absolute** ( $T_c = 25^\circ C$  unless otherwise specified):

Symbol	Parameter	Rating	Units
$V_{DSS}$	Drain-to-Source Voltage	-40	V
$I_D$	Continuous Drain Current	-12	A
	Continuous Drain Current $T_c = 70^\circ C$	-9.6	A
$I_{DM}^{a1}$	Pulsed Drain Current	-48	A
$V_{GS}$	Gate-to-Source Voltage	$\pm 20$	V
$E_{as}^{a5}$	$L=0.5mH$	90	$mJ$
$dv/dt^{a3}$	Peak Diode Recovery $dv/dt$	5.0	V/ns
$P_D$	Power Dissipation	45	W
$T_J, T_{stg}$	Operating Junction and Storage Temperature Range	150, -55 to 150	°C
$T_L$	Maximum Temperature for Soldering	300	°C



# GL12P40A4

## GL Silicon P-Channel Power MOSFET

**Electrical Characteristics** ( $T_c = 25^\circ\text{C}$  unless otherwise specified):

### OFF Characteristics

Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
$V_{DSS}$	Drain to Source Breakdown Voltage	$V_{GS}=0\text{V}, I_D=250\mu\text{A}$	-40	--	--	V
$I_{DSS}$	Drain to Source Leakage Current	$V_{DS}=-40\text{V}, V_{GS}=0\text{V}, T_a=25^\circ\text{C}$	--	--	1.0	$\mu\text{A}$
$I_{GSS(F)}$	Gate to Source Forward Leakage	$V_{GS}=+20\text{V}$	--	--	0.1	$\mu\text{A}$
$I_{GSS(R)}$	Gate to Source Reverse Leakage	$V_{GS}=-20\text{V}$	--	--	-0.1	$\mu\text{A}$

### ON Characteristics<sup>a3</sup>

Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
$R_{DS(ON)1}$	Drain-to-Source On-Resistance	$V_{GS}=-10\text{V}, I_D=-8\text{A}$	--	26	35	$\text{m}\Omega$
$R_{DS(ON)2}$	Drain-to-Source On-Resistance	$V_{GS}=-4.5\text{V}, I_D=-4\text{A}$	--	34	45	$\text{m}\Omega$
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	-1	--	-3.0	V
Pulse width $t_p \leq 380\mu\text{s}, \delta \leq 2\%$						

### Dynamic Characteristics<sup>a4</sup>

Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
$g_{fs}$	Forward Transconductance	$V_{DS}=-15\text{V}, I_D=-8\text{A}$	20	--	--	S
$C_{iss}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=-20\text{V}$	--	530	--	pF
$C_{oss}$	Output Capacitance	$f=1.0\text{MHz}$	--	100	--	
$C_{rss}$	Reverse Transfer Capacitance		--	65	--	

### Resistive Switching Characteristics<sup>a4</sup>

Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
$t_{d(ON)}$	Turn-on Delay Time	$V_{DD}=-20\text{V}, I_D=-12\text{A}$	--	8.8	--	ns
$t_r$	Rise Time		--	6.5	--	
$t_{d(OFF)}$	Turn-Off Delay Time		--	20	--	
$t_f$	Fall Time		--	8	--	
$Q_g$	Total Gate Charge	$V_{DD}=-20\text{V}, I_D=-12\text{A}$	--	15	--	nC
$Q_{gs}$	Gate to Source Charge		--	4.5	--	
$Q_{gd}$	Gate to Drain ( "Miller" )Charge		--	3.5	--	

**Source-Drain Diode Characteristics**

Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
I <sub>S</sub>	Continuous Source Current <sup>a2</sup> (Body Diode)		--	--	-12	A
V <sub>SD</sub>	Diode Forward Voltage <sup>a3</sup>	I <sub>S</sub> =-12A, V <sub>GS</sub> =0V	--	--	-1.5	V
t <sub>rr</sub>	Reverse Recovery Time	I <sub>S</sub> =-12A, T <sub>j</sub> = 25°C	--	45	--	ns
Q <sub>rr</sub>	Reverse Recovery Charge	dI <sub>F</sub> /dt=100A/us, V <sub>GS</sub> =0V	--	40	--	nC

Symbol	Parameter	Typ.	Units
R <sub>θJC</sub>	Junction-to-Case <sup>a2</sup>	2.5	°C/W

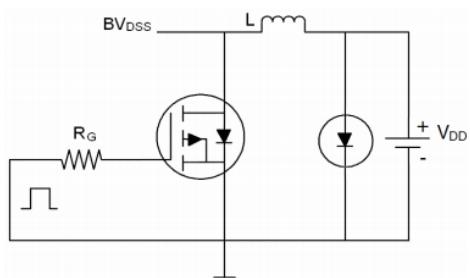
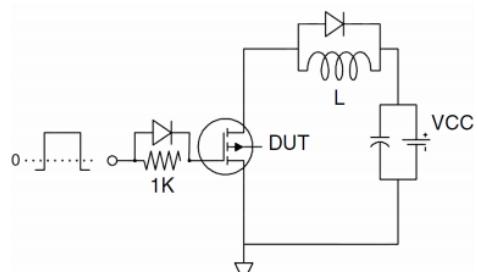
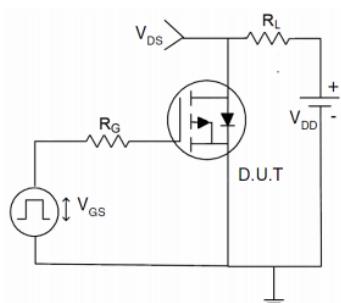
<sup>a1</sup>: Repetitive Rating: Pulse width limited by maximum junction temperature.

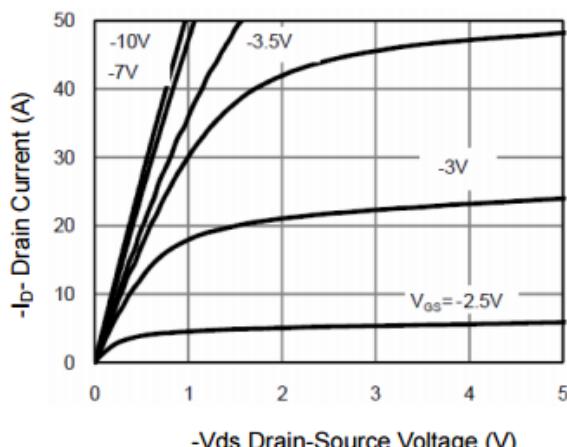
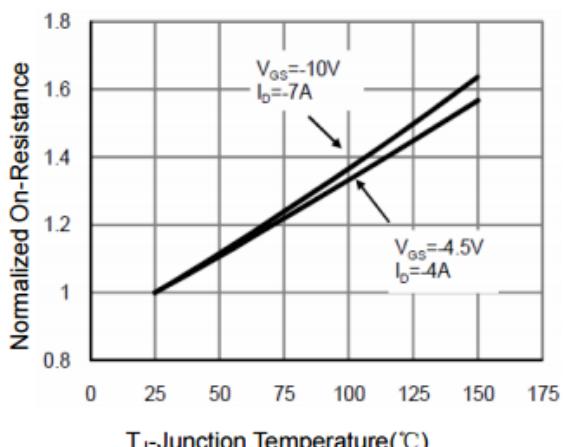
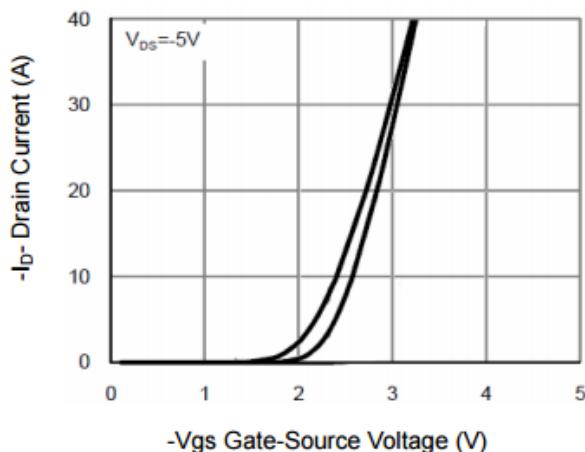
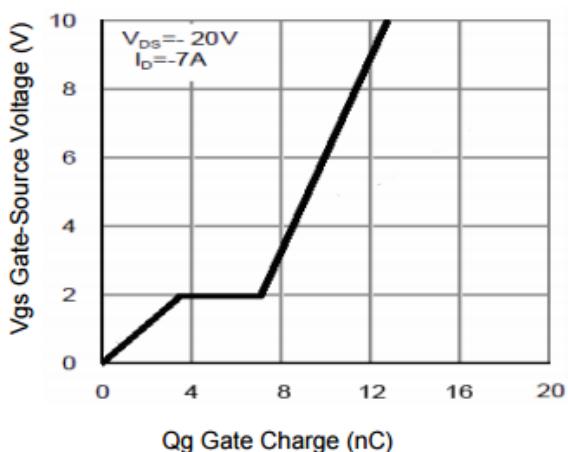
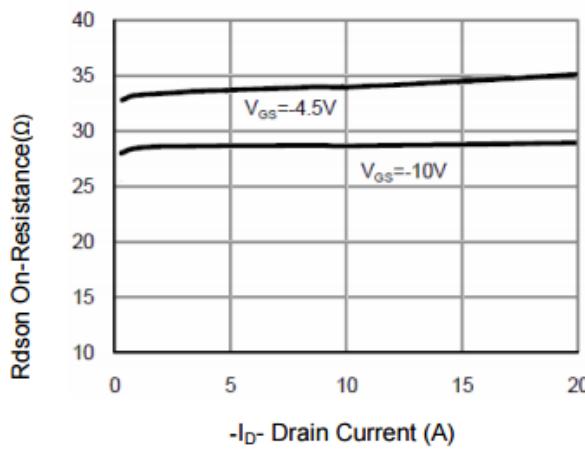
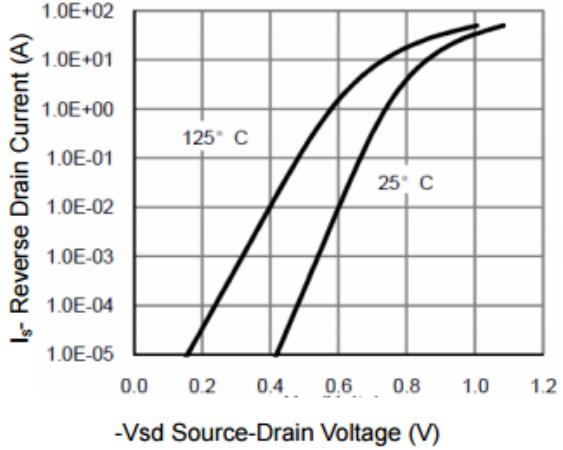
<sup>a2</sup>: Surface Mounted on FR4 Board, t≤10sec.

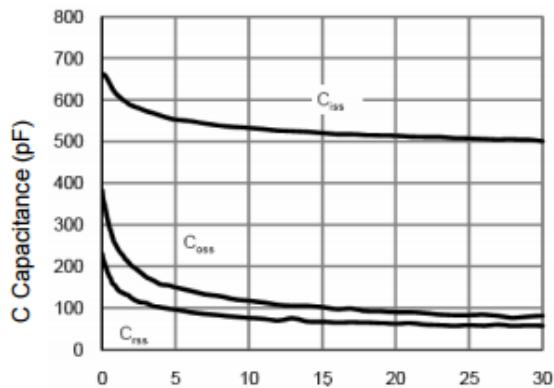
<sup>a3</sup>: Pulse Test: Pulse Width≤300μs, Duty Cycle≤2%.

<sup>a4</sup>: Guaranteed by design, not subject to production

<sup>a5</sup>: T<sub>j</sub>=25°C, V<sub>DD</sub>=15V, V<sub>G</sub>=10V, L=0.5Mh

**Test Circuit**
**1) E<sub>AS</sub> Test Circuit**

**2) Gate Charge Test Circuit**

**3) Switch Time Test Circuit**


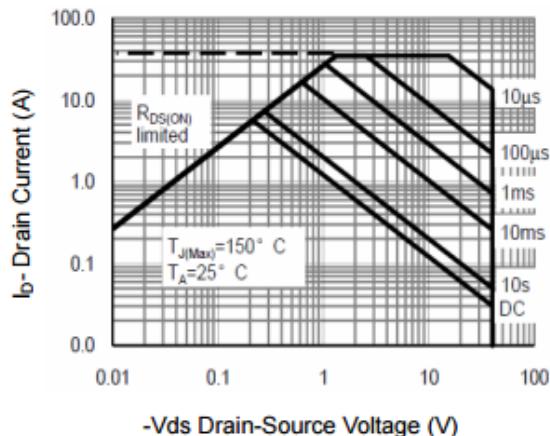
**Typical Electrical and Thermal Characteristics (Curves)**

**Figure 1 Output Characteristics**

**Figure 4 Rdson-Junction Temperature**

**Figure 2 Transfer Characteristics**

**Figure 5 Gate Charge**

**Figure 3 Rdson-Drain Current**

**Figure 6 Source-Drain Diode Forward**



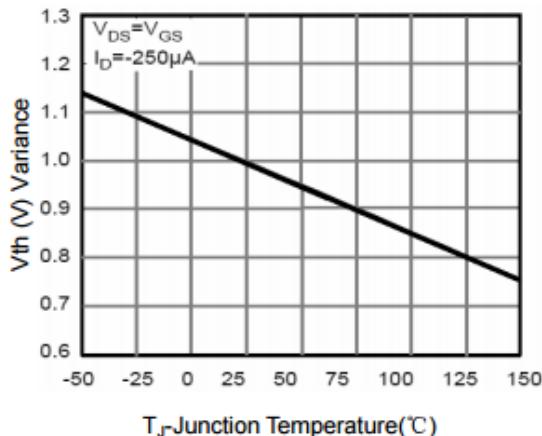
**Figure 7 Capacitance vs Vds**



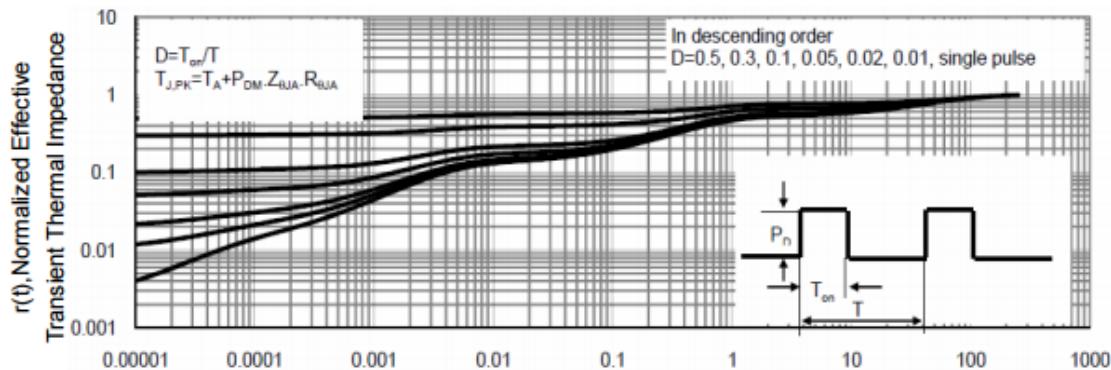
**Figure 9 Power Dissipation**



**Figure 8 Safe Operation Area**



**Figure 10  $V_{GS(\text{th})}$  vs Junction Temperature**



**Figure 11 Normalized Maximum Transient Thermal Impedance**